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|-----------------------------------|--|-------------------------|---|-------------|
| Notice of References Cited | | Application/Control No. | Applicant(s)/Patent Under Reexamination | |
| | | 10/535,033 | SODERLUND, MARCUS | |
| | | Examiner | Art Unit | Page 1 of 2 |
| | | APRIL S. GUZMAN | 2618 | |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------------|----------------|
| * | A | US-5,278,725 A | 01-1994 | Konno et al. | 361/680 |
| * | B | US-5,363,089 A | 11-1994 | Goldenberg, Michael P. | 340/7.63 |
| * | C | US-5,966,777 A | 10-1999 | Jantschek, Robert J. | 16/354 |
| * | D | US-5,987,704 A | 11-1999 | Tang, John G. | 16/354 |
| * | E | US-6,344,977 B1 | 02-2002 | Takagi, Hisamitsu | 361/814 |
| * | F | US-2002/0135993 A1 | 09-2002 | Ueyama et al. | 361/814 |
| * | G | US-6,466,202 B1 | 10-2002 | Suso et al. | 345/169 |
| * | H | US-6,519,812 B2 | 02-2003 | Ko et al. | 16/354 |
| * | I | US-2003/0112589 A1 | 06-2003 | Shimano et al. | 361/683 |
| * | J | US-2006/0034601 A1 | 02-2006 | Andersson et al. | 396/157 |
| * | K | US-2003/0112588 A1 | 06-2003 | Shimano, Kenji | 361/683 |
| * | L | US-2003/0228847 A1 | 12-2003 | Matsumoto, Mitsuyoshi | 455/90.3 |
| * | M | US-6,728,557 B1 | 04-2004 | Tracy et al. | 455/575.3 |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
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| | T | | | | | |

NON-PATENT DOCUMENTS

| | | |
|---|---|---|
| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

| | | | | |
|-----------------------------------|--|-------------------------|---|-------------|
| Notice of References Cited | | Application/Control No. | Applicant(s)/Patent Under Reexamination | |
| | | 10/535,033 | SODERLUND, MARCUS | |
| | | Examiner | Art Unit | Page 2 of 2 |
| | | APRIL S. GUZMAN | 2618 | |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|----------------------------|----------------|
| * | A | US-6,754,514 B1 | 06-2004 | Nakamura, Futoshi | 455/575.3 |
| * | B | US-6,798,649 B1 | 09-2004 | Olodort et al. | 361/683 |
| * | C | US-2004/0212956 A1 | 10-2004 | Kuivas et al. | 361/683 |
| * | D | US-2004/0198474 A1 | 10-2004 | Jung et al. | 455/575.1 |
| * | E | US-6,900,981 B2 | 05-2005 | Kuivas et al. | 361/683 |
| * | F | US-2005/0239520 A1 | 10-2005 | Stefansen, Mads Schenstrom | 455/575.1 |
| * | G | US-2005/0261040 A1 | 11-2005 | Andersson et al. | 455/575.3 |
| * | H | US-2006/0007648 A1 | 01-2006 | Wang, John C. | 361/683 |
| * | I | US-6,990,355 B2 | 01-2006 | Ueyama et al. | 455/550.1 |
| * | J | US-2006/0034601 A1 | 02-2006 | Andersson et al. | 396/157 |
| * | K | US-7,016,712 B2 | 03-2006 | Newman et al. | 455/575.3 |
| * | L | US-7,130,591 B2 | 10-2006 | Iwai et al. | 455/90.3 |
| * | M | US-2006/0227102 A1 | 10-2006 | Finke-Anlauff et al. | 345/156 |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
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NON-PATENT DOCUMENTS

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|---|---|---|
| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
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| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.